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## Intel - 5SGXEA5N2F45I2L Datasheet



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#### Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

D	e	ta	il	ls

Details	
Product Status	Obsolete
Number of LABs/CLBs	185000
Number of Logic Elements/Cells	490000
Total RAM Bits	46080000
Number of I/O	840
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1932-BBGA, FCBGA
Supplier Device Package	1932-FBGA, FC (45x45)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgxea5n2f45i2l

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Symbol	Description	Devices	Minimum <sup>(4)</sup>	Typical	Maximum <sup>(4)</sup>	Unit
			0.82	0.85	0.88	V
V <sub>CCR_GXBR</sub>	Passiver analog power supply (right side)	GX, GS, GT	0.87	0.90	0.93	
(2)	Receiver analog power supply (right side)	un, us, ui	0.97	1.0	1.03	v
			1.03	1.05	1.07	
V <sub>CCR_GTBR</sub>	Receiver analog power supply for GT channels (right side)	GT	1.02	1.05	1.08	V
			0.82	0.85	0.88	
V <sub>CCT_GXBL</sub>	Transmitter analog power supply (left side)	GX, GS, GT	0.87	0.90	0.93	V
(2)			0.97	1.0	1.03	
			1.03	1.05	1.07	
		GX, GS, GT	0.82	0.85	0.88	V
V <sub>CCT_GXBR</sub>	Transmitter analog nower supply (right side)		0.87	0.90	0.93	
(2)	Transmitter analog power supply (right side)		0.97	1.0	1.03	
			1.03	1.05	1.07	
V <sub>CCT_GTBR</sub>	Transmitter analog power supply for GT channels (right side)	GT	1.02	1.05	1.08	V
$V_{CCL\_GTBR}$	Transmitter clock network power supply	GT	1.02	1.05	1.08	V
V <sub>CCH_GXBL</sub>	Transmitter output buffer power supply (left side)	GX, GS, GT	1.425	1.5	1.575	V
V <sub>CCH_GXBR</sub>	Transmitter output buffer power supply (right side)	GX, GS, GT	1.425	1.5	1.575	V

Table 7.	Recommended Transceiver Power Supply Operating Conditions for Stratix V GX,	GS, and GT Devices
(Part 2	of 2)	

#### Notes to Table 7:

(1) This supply must be connected to 3.0 V if the CMU PLL, receiver CDR, or both, are configured at a base data rate > 6.5 Gbps. Up to 6.5 Gbps, you can connect this supply to either 3.0 V or 2.5 V.

(2) Refer to Table 8 to select the correct power supply level for your design.

(3) When using ATX PLLs, the supply must be 3.0 V.

(4) This value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

			<b>Resistance Tolerance</b>				
Symbol	Description	Conditions	C1	C2,I2	C3, I3, I3YY	C4, I4	Unit
50-Ω R <sub>S</sub>	Internal series termination without calibration (50- $\Omega$ setting)	$V_{CCIO} = 1.8$ and 1.5 V	±30	±30	±40	±40	%
50-Ω R <sub>S</sub>	Internal series termination without calibration (50- $\Omega$ setting)	V <sub>CCI0</sub> = 1.2 V	±35	±35	±50	±50	%
100-Ω R <sub>D</sub>	Internal differential termination (100- $\Omega$ setting)	V <sub>CCPD</sub> = 2.5 V	±25	±25	±25	±25	%

Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 2 of 2)

Calibration accuracy for the calibrated series and parallel OCTs are applicable at the moment of calibration. When voltage and temperature conditions change after calibration, the tolerance may change.

OCT calibration is automatically performed at power-up for OCT-enabled I/Os. Table 13 lists the OCT variation with temperature and voltage after power-up calibration. Use Table 13 to determine the OCT variation after power-up calibration and Equation 1 to determine the OCT variation without recalibration.

### Equation 1. OCT Variation Without Recalibration for Stratix V Devices (1), (2), (3), (4), (5), (6)

$$R_{OCT} \,=\, R_{SCAL} \Big( 1 + \langle \frac{dR}{dT} \times \Delta T \rangle \pm \langle \frac{dR}{dV} \times \Delta V \rangle \Big)$$

#### Notes to Equation 1:

- (1) The  $R_{OCT}$  value shows the range of OCT resistance with the variation of temperature and  $V_{CCIO}$ .
- (2) R<sub>SCAL</sub> is the OCT resistance value at power-up.
- (3)  $\Delta T$  is the variation of temperature with respect to the temperature at power-up.
- (4)  $\Delta V$  is the variation of voltage with respect to the V<sub>CCIO</sub> at power-up.
- (5) dR/dT is the percentage change of  $R_{\text{SCAL}}$  with temperature.
- (6) dR/dV is the percentage change of  $\mathsf{R}_{\mathsf{SCAL}}$  with voltage.

Table 13 lists the on-chip termination variation after power-up calibration.

Table 13.	OCT Variation after Power-U	Calibration for Stratix V Devices	(Part 1 of 2) <sup>(1)</sup>
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Symbol	Description	V <sub>CCIO</sub> (V)	Typical	Unit
		3.0	0.0297	
	OCT variation with voltage without recalibration	2.5	0.0344	
dR/dV		1.8	0.0499	%/mV
		1.5	0.0744	
		1.2	0.1241	

- You typically use the interactive Excel-based Early Power Estimator before designing the FPGA to get a magnitude estimate of the device power. The Quartus II PowerPlay Power Analyzer provides better quality estimates based on the specifics of the design after you complete place-and-route. The PowerPlay Power Analyzer can apply a combination of user-entered, simulation-derived, and estimated signal activities that, when combined with detailed circuit models, yields very accurate power estimates.
- **\*** For more information about power estimation tools, refer to the *PowerPlay Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter in the *Quartus II Handbook*.

Symbol/	Conditions	Transceiver Speed Grade 1		Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit	
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
	85– $\Omega$ setting		85 ± 30%		—	85 ± 30%			85 ± 30%		Ω
Differential on-	100–Ω setting	_	100 ± 30%		_	100 ± 30%		_	100 ± 30%		Ω
chip termination resistors <sup>(21)</sup>	120–Ω setting	_	120 ± 30%		_	120 ± 30%		_	120 ± 30%		Ω
	150-Ω setting	_	150 ± 30%	_	_	150 ± 30%		_	150 ± 30%		Ω
V <sub>ICM</sub> (AC and DC	V <sub>CCR_GXB</sub> = 0.85 V or 0.9 V full bandwidth		600		_	600	_		600		mV
	V <sub>CCR_GXB</sub> = 0.85 V or 0.9 V half bandwidth	_	600	_	_	600	_	_	600	_	mV
coupled)	V <sub>CCR_GXB</sub> = 1.0 V/1.05 V full bandwidth	_	700		_	700			700		mV
	V <sub>CCR_GXB</sub> = 1.0 V half bandwidth		750	_	_	750	_	_	750	_	mV
t <sub>LTR</sub> <sup>(11)</sup>	_	_	—	10	—	—	10	—	—	10	μs
t <sub>LTD</sub> (12)	_	4			4			4			μs
t <sub>LTD_manual</sub> <sup>(13)</sup>		4			4			4	_		μs
t <sub>LTR_LTD_manual</sub> <sup>(14)</sup>		15			15	—		15	—		μs
Run Length	_	_		200		—	200		—	200	UI
Programmable equalization (AC Gain) <sup>(10)</sup>	Full bandwidth (6.25 GHz) Half bandwidth (3.125 GHz)			16	_		16	_		16	dB

 Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 4 of 7)

Table 26 shows the approximate maximum data rate using the 10G PCS.

Table 26. Stratix V 10G PCS Approximate Maximum Data Rate (1)
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Mada (2)	Transceiver	PMA Width	64	40	40	40	32	32	
Mode <sup>(2)</sup>	Speed Grade	PCS Width	64	66/67	50	40	32         64/66/67         13.6         12.5         10.88	32	
2	1	C1, C2, C2L, I2, I2L core speed grade	14.1	14.1	10.69	14.1	13.6	13.6	
	2	C1, C2, C2L, I2, I2L core speed grade	12.5	12.5	10.69	12.5	12.5	12.5	
	2	C3, I3, I3L core speed grade	12.5	12.5	10.69	12.5	10.88	10.88	
FIFO or Register	3	C1, C2, C2L, I2, I2L core speed grade							
		C3, I3, I3L core speed grade	8.5 Gbps						
		C4, I4 core speed grade							
		I3YY core speed grade	10.3125 Gbps						

Notes to Table 26:

(1) The maximum data rate is in Gbps.

(2) The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.

# Table 28. Transceiver Specifications for Stratix V GT Devices (Part 2 of 5)<sup>(1)</sup>

Symbol/	Conditions	Transceiver Speed Grade 2		SI	Unit			
Description		Min	Тур	Max	Min	Тур	Max	
	100 Hz			-70			-70	
Transmitter REFCLK Phase Noise (622	1 kHz			-90	_	_	-90	-
	10 kHz			-100	_	_	-100	dBc/Hz
MHz) <sup>(18)</sup>	100 kHz		—	-110	_	—	-110	-
	$\geq$ 1 MHz		—	-120	_	—	-120	-
Transmitter REFCLK Phase Jitter (100 MHz) <sup>(15)</sup>	10 kHz to 1.5 MHz (PCIe)		_	3	_		3	ps (rms)
RREF <sup>(17)</sup>	—		1800 ± 1%	_	_	1800 ± 1%	_	Ω
Transceiver Clocks								
fixedclk <b>clock</b> frequency	PCIe Receiver Detect		100 or 125	_	_	100 or 125	_	MHz
Reconfiguration clock (mgmt_clk_clk) frequency	_	100	_	125	100	_	125	MHz
Receiver				•				
Supported I/O Standards	—		1.4-V PCMI	_, 1.5-V PCM	L, 2.5-V PCI	ML, LVPEC	L, and LVDS	3
Data rate (Standard PCS) <sup>(21)</sup>	GX channels	600	_	8500	600	_	8500	Mbps
Data rate (10G PCS) <sup>(21)</sup>	GX channels	600	_	12,500	600	_	12,500	Mbps
Data rate	GT channels	19,600	—	28,050	19,600	—	25,780	Mbps
Absolute V <sub>MAX</sub> for a receiver pin <sup>(3)</sup>	GT channels	_	_	1.2	_	_	1.2	V
Absolute V <sub>MIN</sub> for a receiver pin	GT channels	-0.4	_	_	-0.4		_	V
Maximum peak-to-peak	GT channels	_	—	1.6	—	—	1.6	V
differential input voltage V <sub>ID</sub> (diff p-p) before device configuration <sup>(20)</sup>	GX channels				(8)			
	GT channels							
Maximum peak-to-peak differential input voltage $V_{ID}$ (diff p-p) after device configuration ( <sup>16</sup> ), ( <sup>20</sup> )	V <sub>CCR_GTB</sub> = 1.05 V (V <sub>ICM</sub> = 0.65 V)	—	-	2.2	_	_	2.2	V
oomguration ( ), ( )	GX channels		•	•	(8)			
Minimum differential	GT channels	200	_		200			mV
eye opening at receiver serial input pins <sup>(4)</sup> , <sup>(20)</sup>	GX channels				(8)			

#### Table 31. PLL Specifications for Stratix V Devices (Part 3 of 3)

Symbol	Parameter		Тур	Max	Unit
f <sub>RES</sub>	Resolution of VCO frequency ( $f_{INPFD} = 100 \text{ MHz}$ )	390625	5.96	0.023	Hz

#### Notes to Table 31:

(1) This specification is limited in the Quartus II software by the I/O maximum frequency. The maximum I/O frequency is different for each I/O standard.

(2) This specification is limited by the lower of the two: I/O  $f_{MAX}$  or  $f_{OUT}$  of the PLL.

- (3) A high input jitter directly affects the PLL output jitter. To have low PLL output clock jitter, you must provide a clean clock source < 120 ps.
- (4)  $f_{REF}$  is fIN/N when N = 1.
- (5) Peak-to-peak jitter with a probability level of 10<sup>-12</sup> (14 sigma, 99.9999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL, when an input jitter of 30 ps is applied. The external memory interface clock output jitter specifications use a different measurement method and are available in Table 44 on page 52.
- (6) The cascaded PLL specification is only applicable with the following condition: a. Upstream PLL: 0.59Mhz ≤ Upstream PLL BW < 1 MHz b. Downstream PLL: Downstream PLL BW > 2 MHz
- (7) High bandwidth PLL settings are not supported in external feedback mode.
- (8) The external memory interface clock output jitter specifications use a different measurement method, which is available in Table 42 on page 50.
- (9) The VCO frequency reported by the Quartus II software in the PLL Usage Summary section of the compilation report takes into consideration the VCO post-scale counter K value. Therefore, if the counter K has a value of 2, the frequency reported can be lower than the f<sub>VCO</sub> specification.
- (10) This specification only covers fractional PLL for low bandwidth. The  $f_{VCO}$  for fractional value range 0.05 0.95 must be  $\geq$  1000 MHz, while  $f_{VCO}$  for fractional value range 0.20 0.80 must be  $\geq$  1200 MHz.
- (11) This specification only covered fractional PLL for low bandwidth. The  $f_{VC0}$  for fractional value range 0.05-0.95 must be  $\geq$  1000 MHz.
- (12) This specification only covered fractional PLL for low bandwidth. The  $f_{VC0}$  for fractional value range 0.20-0.80 must be  $\geq$  1200 MHz.

#### **DSP Block Specifications**

Table 32 lists the Stratix V DSP block performance specifications.

			I	Peforman	ce			
Mode	C1	C2, C2L	12, 12L	C3	13, 13L, 13YY	C4	14	Unit
		Modes ι	ising one	DSP				4
Three 9 x 9	600	600	600	480	480	420	420	MHz
One 18 x 18	600	600	600	480	480	420	400	MHz
Two partial 18 x 18 (or 16 x 16)	600	600	600	480	480	420	400	MHz
One 27 x 27	500	500	500	400	400	350	350	MHz
One 36 x 18	500	500	500	400	400	350	350	MHz
One sum of two 18 x 18(One sum of 2 16 x 16)	500	500	500	400	400	350	350	MHz
One sum of square	500	500	500	400	400	350	350	MHz
One 18 x 18 plus 36 (a x b) + c	500	500	500	400	400	350	350	MHz
		Modes u	sing two l	DSPs	1		•	1
Three 18 x 18	500	500	500	400	400	350	350	MHz
One sum of four 18 x 18	475	475	475	380	380	300	300	MHz
One sum of two 27 x 27	465	465	450	380	380	300	290	MHz
One sum of two 36 x 18	475	475	475	380	380	300	300	MHz
One complex 18 x 18	500	500	500	400	400	350	350	MHz
One 36 x 36	475	475	475	380	380	300	300	MHz

#### Table 32. Block Performance Specifications for Stratix V DSP Devices (Part 1 of 2)

0b.al	Oanditiana		C1		C2,	C2L, I	2, I2L	C3,	13, 131	., <b>I</b> 3YY	C4,14			Ilnit
Symbol	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
Transmitter				<u>.</u>						<u>.</u>				
	SERDES factor J = 3 to 10 <sup>(9)</sup> , <sup>(11)</sup> , <sup>(12)</sup> , <sup>(13)</sup> , <sup>(14)</sup> , <sup>(15)</sup> , <sup>(16)</sup>	(6)		1600	(6)		1434	(6)		1250	(6)		1050	Mbps
	SERDES factor J $\geq 4$													
True Differential I/O Standards	LVDS TX with DPA <sup>(12)</sup> , <sup>(14)</sup> , <sup>(15)</sup> , <sup>(16)</sup>	(6)	_	1600	(6)	_	1600	(6)	_	1600	(6)	_	1250	Mbps
- f <sub>HSDR</sub> (data rate)	SERDES factor J = 2, uses DDR Registers	(6)		(7)	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	Mbps
	SERDES factor J = 1, uses SDR Register	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	Mbps
Emulated Differential I/O Standards with Three External Output Resistor Networks - f <sub>HSDR</sub> (data rate) <sup>(10)</sup>	SERDES factor J = 4 to 10 $(17)$	(6)		1100	(6)		1100	(6)		840	(6)		840	Mbps
t <sub>x Jitter</sub> - True Differential	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	_		160	_	_	160			160	_	_	160	ps
I/O Standards	Total Jitter for Data Rate < 600 Mbps	_	_	0.1	_	_	0.1	_	_	0.1	_	_	0.1	UI
t <sub>x Jitter</sub> - Emulated Differential I/O Standards	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	_		300	_		300	_	_	300	_		325	ps
with Three External Output Resistor Network	Total Jitter for Data Rate < 600 Mbps	_		0.2			0.2			0.2	_		0.25	UI

# Table 36. High-Speed I/O Specifications for Stratix V Devices <sup>(1), (2)</sup> (Part 2 of 4)

i ani o o o i i i i gii	-Speed I/U Specifica		C1				2, I2L		-	., I3YY		C4,I	A	
Symbol	Conditions				-	-	-		-	-		-		Unit
		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
t <sub>duty</sub>	Transmitter output clock duty cycle for both True and Emulated Differential I/O Standards	45	50	55	45	50	55	45	50	55	45	50	55	%
	True Differential I/O Standards	_	_	160	_	_	160	_	_	200	_	_	200	ps
t <sub>rise</sub> & t <sub>fall</sub>	Emulated Differential I/O Standards with three external output resistor networks			250			250			250			300	ps
	True Differential I/O Standards	_	_	150	_	_	150	_	_	150	_	_	150	ps
TCCS	Emulated Differential I/O Standards	_		300	_	_	300	_	_	300	_	_	300	ps
Receiver														
	SERDES factor J = 3 to 10 (11), (12), (13), (14), (15), (16)	150		1434	150	_	1434	150	_	1250	150	_	1050	Mbps
True Differential I/O Standards	SERDES factor J ≥ 4 LVDS RX with DPA (12), (14), (15), (16)	150		1600	150		1600	150		1600	150		1250	Mbps
- f <sub>HSDRDPA</sub> (data rate)	SERDES factor J = 2, uses DDR Registers	(6)		(7)	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	Mbps
	SERDES factor J = 1, uses SDR Register	(6)		(7)	(6)		(7)	(6)		(7)	(6)		(7)	Mbps

# Table 36. High-Speed I/O Specifications for Stratix V Devices (1), (2) (Part 3 of 4)

Gumbal	Conditions		C1		C2,	C2L, I	2, I2L	C3,	13, I3L	., I <b>3</b> YY		C4,I	4	II.a.iA
Symbol	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
	SERDES factor J = 3 to 10	(6)	_	(8)	(6)	_	(8)	(6)	_	(8)	(6)		(8)	Mbps
f <sub>HSDR</sub> (data rate)	SERDES factor J = 2, uses DDR Registers	(6)		(7)	(6)	_	(7)	(6)		(7)	(6)		(7)	Mbps
	SERDES factor J = 1, uses SDR Register	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	(6)		(7)	Mbps
DPA Mode														
DPA run length	_			1000 0			1000 0		_	1000 0		_	1000 0	UI
Soft CDR mode	•													
Soft-CDR PPM tolerance	_	_	_	300	_	_	300	_	_	300	_		300	± PPM
Non DPA Mode	Non DPA Mode													
Sampling Window	—			300			300			300			300	ps

#### Table 36. High-Speed I/O Specifications for Stratix V Devices <sup>(1), (2)</sup> (Part 4 of 4)

Notes to Table 36:

(1) When J = 3 to 10, use the serializer/deserializer (SERDES) block.

(2) When J = 1 or 2, bypass the SERDES block.

(3) This only applies to DPA and soft-CDR modes.

(4) Clock Boost Factor (W) is the ratio between the input data rate to the input clock rate.

(5) This is achieved by using the **LVDS** clock network.

(6) The minimum specification depends on the clock source (for example, the PLL and clock pin) and the clock routing resource (global, regional, or local) that you use. The I/O differential buffer and input register do not have a minimum toggle rate.

(7) The maximum ideal frequency is the SERDES factor (J) x the PLL maximum output frequency (fOUT) provided you can close the design timing and the signal integrity simulation is clean.

(8) You can estimate the achievable maximum data rate for non-DPA mode by performing link timing closure analysis. You must consider the board skew margin, transmitter delay margin, and receiver sampling margin to determine the maximum data rate supported.

(9) If the receiver with DPA enabled and transmitter are using shared PLLs, the minimum data rate is 150 Mbps.

(10) You must calculate the leftover timing margin in the receiver by performing link timing closure analysis. You must consider the board skew margin, transmitter channel-to-channel skew, and receiver sampling margin to determine leftover timing margin.

(11) The F<sub>MAX</sub> specification is based on the fast clock used for serial data. The interface F<sub>MAX</sub> is also dependent on the parallel clock domain which is design-dependent and requires timing analysis.

(12) Stratix V RX LVDS will need DPA. For Stratix V TX LVDS, the receiver side component must have DPA.

(13) Stratix V LVDS serialization and de-serialization factor needs to be x4 and above.

(14) Requires package skew compensation with PCB trace length.

(15) Do not mix single-ended I/O buffer within LVDS I/O bank.

(16) Chip-to-chip communication only with a maximum load of 5 pF.

(17) When using True LVDS RX channels for emulated LVDS TX channel, only serialization factors 1 and 2 are supported.

Speed Grade	Min	Max	Unit
C4,I4	8	16	ps

#### Table 40. DQS Phase Offset Delay Per Setting for Stratix V Devices <sup>(1), (2)</sup> (Part 2 of 2)

#### Notes to Table 40:

(1) The typical value equals the average of the minimum and maximum values.

(2) The delay settings are linear with a cumulative delay variation of 40 ps for all speed grades. For example, when using a -2 speed grade and applying a 10-phase offset setting to a 90° phase shift at 400 MHz, the expected average cumulative delay is [625 ps + (10 × 10 ps) ± 20 ps] = 725 ps ± 20 ps.

Table 41 lists the DQS phase shift error for Stratix V devices.

Table 41. DQS Phase Shift Error Specification for DLL-Delayed Clock (t<sub>DQS\_PSERR</sub>) for Stratix V Devices <sup>(1)</sup>

Number of DQS Delay Buffers	C1	C2, C2L, I2, I2L	C3, I3, I3L, I3YY	C4,14	Unit
1	28	28	30	32	ps
2	56	56	60	64	ps
3	84	84	90	96	ps
4	112	112	120	128	ps

Notes to Table 41:

(1) This error specification is the absolute maximum and minimum error. For example, skew on three DQS delay buffers in a -2 speed grade is  $\pm 78$  ps or  $\pm 39$  ps.

Table 42 lists the memory output clock jitter specifications for Stratix V devices.

Clock Network	Parameter Symb		C1 Symbol		C2, C2L, I2, I2L		C3, I3, I3L, I3YY		C4,14		Unit
NELWUIK		-	Min	Max	Min	Max	Min	Max	Min	Max	
	Clock period jitter	$t_{JIT(per)}$	-50	50	-50	50	-55	55	-55	55	ps
Regional	Cycle-to-cycle period jitter	$t_{\text{JIT(cc)}}$	-100	100	-100	100	-110	110	-110	110	ps
	Duty cycle jitter	$t_{\text{JIT}(\text{duty})}$	-50	50	-50	50	-82.5	82.5	-82.5	82.5	ps
	Clock period jitter	$t_{JIT(per)}$	-75	75	-75	75	-82.5	82.5	-82.5	82.5	ps
Global	Cycle-to-cycle period jitter	$t_{\rm JIT(cc)}$	-150	150	-150	150	-165	165	-165	165	ps
	Duty cycle jitter	$t_{JIT(duty)}$	-75	75	-75	75	-90	90	-90	90	ps

	Member		Active Serial (1)	)	Fast Passive Parallel <sup>(2)</sup>					
Variant	Code	Width	DCLK (MHz)	Min Config Time (s)	Width	DCLK (MHz)	Min Config Time (s)			
	D3	4	100	0.344	32	100	0.043			
	D4	4	100	0.534	32	100	0.067			
GS		4	100	0.344	32	100	0.043			
65	D5	4	100	0.534	32	100	0.067			
	D6	4	100	0.741	32	100	0.093			
	D8	4	100	0.741	32	100	0.093			
Е	E9	4	100	0.857	32	100	0.107			
	EB	4	100	0.857	32	100	0.107			

Table 48. Minimum Configuration Time Estimation for Stratix V Devices

#### Notes to Table 48:

(1) DCLK frequency of 100 MHz using external CLKUSR.

(2) Max FPGA FPP bandwidth may exceed bandwidth available from some external storage or control logic.

# **Fast Passive Parallel Configuration Timing**

This section describes the fast passive parallel (FPP) configuration timing parameters for Stratix V devices.

# DCLK-to-DATA[] Ratio for FPP Configuration

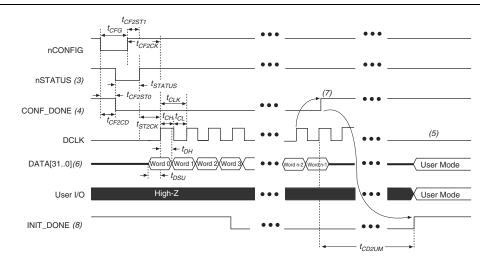
FPP configuration requires a different DCLK-to-DATA[]ratio when you enable the design security, decompression, or both features. Table 49 lists the DCLK-to-DATA[]ratio for each combination.

Configuration Scheme	Decompression	Design Security	DCLK-to-DATA[] Ratio
	Disabled	Disabled	1
FPP ×8	Disabled	Enabled	1
FFF X0	Enabled	Disabled	2
	Enabled	Enabled	2
	Disabled	Disabled	1
FPP ×16	Disabled	Enabled	2
FFF ×10	Enabled	Disabled	4
	Enabled	Enabled	4

 Table 49. DCLK-to-DATA[] Ratio <sup>(1)</sup> (Part 1 of 2)

# FPP Configuration Timing when DCLK-to-DATA [] = 1

Figure 12 shows the timing waveform for FPP configuration when using a MAX II or MAX V device as an external host. This waveform shows timing when the DCLK-to-DATA[] ratio is 1.





#### Notes to Figure 12:

- (1) Use this timing waveform when the DCLK-to-DATA [] ratio is 1.
- (2) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF\_DONE are at logic-high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (3) After power-up, the Stratix V device holds nstatus low for the time of the POR delay.
- (4) After power-up, before and during configuration, CONF\_DONE is low.
- (5) Do not leave DCLK floating after configuration. DCLK is ignored after configuration is complete. It can toggle high or low if required.
- (6) For FPP ×16, use DATA [15..0]. For FPP ×8, use DATA [7..0]. DATA [31..0] are available as a user I/O pin after configuration. The state of this pin depends on the dual-purpose pin settings.
- (7) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF\_DONE is released high when the Stratix V device receives all the configuration data successfully. After CONF\_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (8) After the option bit to enable the INIT\_DONE pin is configured into the device, the INIT DONE goes low.

Table 50 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA[] ratio is 1.

Table 50. FPP Timing Parameters for Stratix V Devices (1)

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CF2CD</sub>	nCONFIG low to CONF_DONE low	—	600	ns
t <sub>CF2ST0</sub>	nCONFIG low to nSTATUS low	—	600	ns
t <sub>CFG</sub>	nCONFIG low pulse width	2	—	μS
t <sub>status</sub>	nSTATUS low pulse width	268	1,506 <sup>(2)</sup>	μS
t <sub>CF2ST1</sub>	nCONFIG high to nSTATUS high	—	1,506 <sup>(3)</sup>	μS
t <sub>CF2CK</sub> (6)	nCONFIG high to first rising edge on DCLK	1,506	_	μS
t <sub>ST2CK</sub> <sup>(6)</sup>	nSTATUS high to first rising edge of DCLK	2	_	μS
t <sub>DSU</sub>	DATA [] setup time before rising edge on DCLK	5.5	_	ns
t <sub>DH</sub>	DATA [] hold time after rising edge on DCLK	0	_	ns
t <sub>CH</sub>	DCLK high time	$0.45\times1/f_{MAX}$	—	S
t <sub>CL</sub>	DCLK low time	$0.45\times1/f_{MAX}$	—	S
t <sub>CLK</sub>	DCLK period	1/f <sub>MAX</sub>	_	S
f	DCLK frequency (FPP ×8/×16)	—	125	MHz
f <sub>MAX</sub>	DCLK frequency (FPP ×32)	—	100	MHz
t <sub>CD2UM</sub>	CONF_DONE high to user mode <sup>(4)</sup>	175	437	μS
+	CONTRACT high to an union analysis	4 × maximum		
t <sub>CD2CU</sub>	CONF_DONE high to CLKUSR enabled	DCLK period	—	
t <sub>CD2UMC</sub>	CONF_DONE high to user mode with CLKUSR option on	$\begin{array}{c} t_{\text{CD2CU}} + \\ (8576 \times \text{CLKUSR} \\ \text{period}) \ ^{(5)} \end{array}$	_	_

#### Notes to Table 50:

(1) Use these timing parameters when the decompression and design security features are disabled.

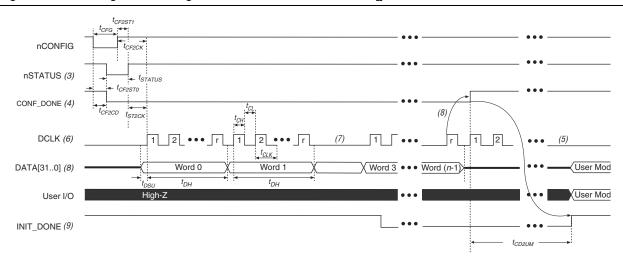
(2) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.

(3) This value is applicable if you do not delay configuration by externally holding the nSTATUS low.

- (4) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.
- (5) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (6) If nSTATUS is monitored, follow the t<sub>ST2CK</sub> specification. If nSTATUS is not monitored, follow the t<sub>CF2CK</sub> specification.

# FPP Configuration Timing when DCLK-to-DATA [] > 1

Figure 13 shows the timing waveform for FPP configuration when using a MAX II device, MAX V device, or microprocessor as an external host. This waveform shows timing when the DCLK-to-DATA [] ratio is more than 1.



#### Figure 13. FPP Configuration Timing Waveform When the DCLK-to-DATA[] Ratio is >1 (1), (2)

#### Notes to Figure 13:

- (1) Use this timing waveform and parameters when the DCLK-to-DATA [] ratio is >1. To find out the DCLK-to-DATA [] ratio for your system, refer to Table 49 on page 55.
- (2) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF\_DONE are at logic high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (3) After power-up, the Stratix V device holds nSTATUS low for the time as specified by the POR delay.
- (4) After power-up, before and during configuration, CONF\_DONE is low.
- (5) Do not leave DCLK floating after configuration. You can drive it high or low, whichever is more convenient.
- (6) "r" denotes the DCLK-to-DATA [] ratio. For the DCLK-to-DATA [] ratio based on the decompression and the design security feature enable settings, refer to Table 49 on page 55.
- (7) If needed, pause DCLK by holding it low. When DCLK restarts, the external host must provide data on the DATA [31..0] pins prior to sending the first DCLK rising edge.
- (8) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF\_DONE is released high after the Stratix V device receives all the configuration data successfully. After CONF\_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (9) After the option bit to enable the INIT DONE pin is configured into the device, the INIT DONE goes low.

Table 54 lists the PS configuration timing parameters for Stratix V devices.

Table 54. PS Timing Parameters for Stratix V Devices

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CF2CD</sub>	nCONFIG low to CONF_DONE low	—	600	ns
t <sub>CF2ST0</sub>	nCONFIG low to nSTATUS low	—	600	ns
t <sub>CFG</sub>	nCONFIG low pulse width	2	—	μS
t <sub>status</sub>	nSTATUS low pulse width	268	1,506 <sup>(1)</sup>	μS
t <sub>CF2ST1</sub>	nCONFIG high to nSTATUS high	—	1,506 <sup>(2)</sup>	μS
t <sub>CF2CK</sub> (5)	nCONFIG high to first rising edge on DCLK	1,506	—	μS
t <sub>ST2CK</sub> <sup>(5)</sup>	nSTATUS high to first rising edge of DCLK	2	—	μS
t <sub>DSU</sub>	DATA[] setup time before rising edge on DCLK	5.5	—	ns
t <sub>DH</sub>	DATA[] hold time after rising edge on DCLK	0	—	ns
t <sub>CH</sub>	DCLK high time	$0.45\times 1/f_{MAX}$	—	S
t <sub>CL</sub>	DCLK low time	$0.45\times 1/f_{MAX}$	—	S
t <sub>CLK</sub>	DCLK period	1/f <sub>MAX</sub>	—	S
f <sub>MAX</sub>	DCLK frequency	—	125	MHz
t <sub>CD2UM</sub>	CONF_DONE high to user mode $(3)$	175	437	μS
t <sub>CD2CU</sub>	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	_	_
t <sub>CD2UMC</sub>	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU}$ + (8576 × CLKUSR period) <sup>(4)</sup>	_	_

#### Notes to Table 54:

(1) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.

(2) This value is applicable if you do not delay configuration by externally holding the nSTATUS low.

(3) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.

(4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the "Initialization" section.

(5) If nSTATUS is monitored, follow the t<sub>ST2CK</sub> specification. If nSTATUS is not monitored, follow the t<sub>CF2CK</sub> specification.

# Initialization

Table 55 lists the initialization clock source option, the applicable configuration schemes, and the maximum frequency.

Table 55. Initialization Clock Source Option and the Maximu
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Initialization Clock Source	Configuration Schemes	Maximum Frequency	Minimum Number of Clock Cycles <sup>(1)</sup>
Internal Oscillator	AS, PS, FPP	12.5 MHz	
CLKUSR	AS, PS, FPP <sup>(2)</sup>	125 MHz	8576
DCLK	PS, FPP	125 MHz	

#### Notes to Table 55:

(1) The minimum number of clock cycles required for device initialization.

(2) To enable CLKUSR as the initialization clock source, turn on the Enable user-supplied start-up clock (CLKUSR) option in the Quartus II software from the General panel of the Device and Pin Options dialog box.

Table 60.	Glossary	(Part 3 of 4)
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Letter	Subject	Definitions		
	SW (sampling window)	Timing Diagram—the period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window, as shown:         Bit Time         0.5 x TCCS       RSKM         Sampling Window       RSKM         0.5 x TCCS       RSKM		
S	Single-ended voltage referenced I/O standard	The JEDEC standard for SSTL and HSTL I/O defines both the AC and DC input signal values.         The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state.         The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing:         Single-Ended Voltage Referenced I/O Standard         VIL(AC)         VIL(AC)         VIL(AC)         VOH         VOL		
	t <sub>C</sub>	High-speed receiver and transmitter input and output clock period.		
	TCCS (channel- to-channel-skew)	The timing difference between the fastest and slowest output edges, including $t_{CO}$ variation and clock skew, across channels driven by the same PLL. The clock is included in the TCCS measurement (refer to the <i>Timing Diagram</i> figure under <b>SW</b> in this table).		
		High-speed I/O block—Duty cycle on the high-speed transmitter output clock.		
т	t <sub>DUTY</sub>	<b>Timing Unit Interval (TUI)</b> The timing budget allowed for skew, propagation delays, and the data sampling window. (TUI = $1/(\text{receiver input clock frequency multiplication factor}) = t_c/w)$		
	t <sub>FALL</sub>	Signal high-to-low transition time (80-20%)         Cycle-to-cycle jitter tolerance on the PLL clock input.		
	t <sub>INCCJ</sub>			
	t <sub>OUTPJ_IO</sub>	Period jitter on the general purpose I/O driven by a PLL.		
	t <sub>outpj_dc</sub>	Period jitter on the dedicated clock output driven by a PLL.		
	<b>t</b> <sub>RISE</sub>	Signal low-to-high transition time (20-80%)		
U	_	_		

Letter	Subject	Definitions
	V <sub>CM(DC)</sub>	DC common mode input voltage.
	V <sub>ICM</sub>	Input common mode voltage—The common mode of the differential signal at the receiver.
	V <sub>ID</sub>	Input differential voltage swing—The difference in voltage between the positive and complementary conductors of a differential transmission at the receiver.
	V <sub>DIF(AC)</sub>	AC differential input voltage—Minimum AC input differential voltage required for switching.
	V <sub>DIF(DC)</sub>	DC differential input voltage— Minimum DC input differential voltage required for switching.
	V <sub>IH</sub>	Voltage input high—The minimum positive voltage applied to the input which is accepted by the device as a logic high.
	V <sub>IH(AC)</sub>	High-level AC input voltage
	V <sub>IH(DC)</sub>	High-level DC input voltage
V	V <sub>IL</sub>	Voltage input low—The maximum positive voltage applied to the input which is accepted by the device as a logic low.
	V <sub>IL(AC)</sub>	Low-level AC input voltage
	V <sub>IL(DC)</sub>	Low-level DC input voltage
	V <sub>OCM</sub>	Output common mode voltage—The common mode of the differential signal at the transmitter.
	V <sub>OD</sub>	Output differential voltage swing—The difference in voltage between the positive and complementary conductors of a differential transmission at the transmitter.
	V <sub>SWING</sub>	Differential input voltage
	V <sub>X</sub>	Input differential cross point voltage
	V <sub>OX</sub>	Output differential cross point voltage
W	W	High-speed I/O block—clock boost factor
X		
Y	_	_
Z		

#### Table 60. Glossary (Part 4 of 4)

Table 61. Document Revision History (Part 3 of 3)

Date	Version	Changes
		■ Updated Table 2, Table 6, Table 7, Table 20, Table 23, Table 27, Table 47, Table 60
May 2013	ay 2013 2.7	■ Added Table 24, Table 48
		Updated Figure 9, Figure 10, Figure 11, Figure 12
February 2013	2.6	<ul> <li>Updated Table 7, Table 9, Table 20, Table 23, Table 27, Table 30, Table 31, Table 35, Table 46</li> </ul>
		<ul> <li>Updated "Maximum Allowed Overshoot and Undershoot Voltage"</li> </ul>
		<ul> <li>Updated Table 3, Table 6, Table 7, Table 8, Table 23, Table 24, Table 25, Table 27, Table 30, Table 32, Table 35</li> </ul>
		Added Table 33
		<ul> <li>Added "Fast Passive Parallel Configuration Timing"</li> </ul>
December 0010	0.5	<ul> <li>Added "Active Serial Configuration Timing"</li> </ul>
December 2012	2.5	<ul> <li>Added "Passive Serial Configuration Timing"</li> </ul>
		<ul> <li>Added "Remote System Upgrades"</li> </ul>
		<ul> <li>Added "User Watchdog Internal Circuitry Timing Specification"</li> </ul>
		<ul> <li>Added "Initialization"</li> </ul>
		<ul> <li>Added "Raw Binary File Size"</li> </ul>
June 2012 2.4		<ul> <li>Added Figure 1, Figure 2, and Figure 3.</li> </ul>
	2.4	<ul> <li>Updated Table 1, Table 2, Table 3, Table 6, Table 11, Table 22, Table 23, Table 27, Table 29, Table 30, Table 31, Table 32, Table 35, Table 38, Table 39, Table 40, Table 41, Table 43, Table 56, and Table 59.</li> </ul>
		<ul> <li>Various edits throughout to fix bugs.</li> </ul>
		<ul> <li>Changed title of document to Stratix V Device Datasheet.</li> </ul>
		Removed document from the Stratix V handbook and made it a separate document.
February 2012	2.3	Updated Table 1–22, Table 1–29, Table 1–31, and Table 1–31.
December 2011	2.2	■ Added Table 2–31.
	2.2	■ Updated Table 2–28 and Table 2–34.
Neurometren 0011	0.1	<ul> <li>Added Table 2–2 and Table 2–21 and updated Table 2–5 with information about Stratix V GT devices.</li> </ul>
November 2011	2.1	<ul> <li>Updated Table 2–11, Table 2–13, Table 2–20, and Table 2–25.</li> </ul>
		<ul> <li>Various edits throughout to fix SPRs.</li> </ul>
		<ul> <li>Updated Table 2–4, Table 2–18, Table 2–19, Table 2–21, Table 2–22, Table 2–23, and Table 2–24.</li> </ul>
May 2011	2.0	<ul> <li>Updated the "DQ Logic Block and Memory Output Clock Jitter Specifications" title.</li> </ul>
		<ul> <li>Chapter moved to Volume 1.</li> </ul>
		<ul> <li>Minor text edits.</li> </ul>
December 2010	1.1	■ Updated Table 1–2, Table 1–4, Table 1–19, and Table 1–23.
		<ul> <li>Converted chapter to the new template.</li> </ul>
		<ul> <li>Minor text edits.</li> </ul>
July 2010	1.0	Initial release.